

Erratum: "Photoluminescence induced by thermal annealing in SrTiO₃ thin film"
[Appl. Phys. Lett. 95, 241906 (2009)]

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Erratum: “Photoluminescence induced by thermal annealing in SrTiO₃ thin film” [Appl. Phys. Lett. 95, 241906 (2009)]

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In Figs. 2 and 3, the numbers in the top *x*-axis (in electron volt unit) do not match with the bottom *x*-axis (in wave number unit). We have corrected the unit conversion error and present the revised Figs. 2 and 3 in this erratum.

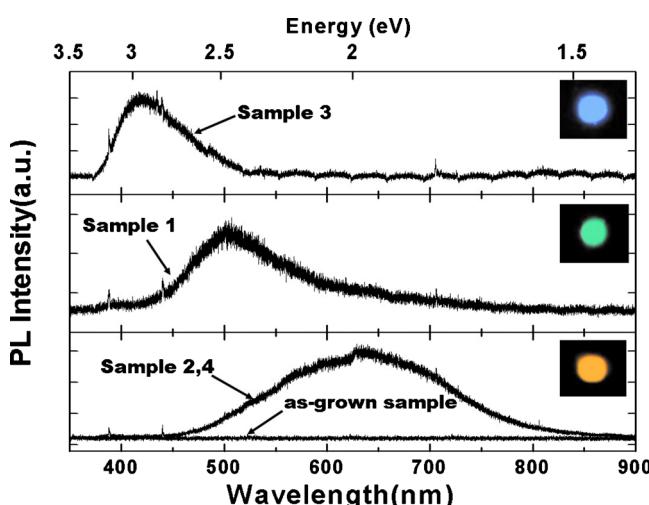


FIG. 2. (Color online) PL spectrum of the postannealed SrTiO₃ films taken at room-temperature. PL data of the as-grown film is shown together. The insets in the three panels show the PL images taken with a digital camera during the laser excitation.

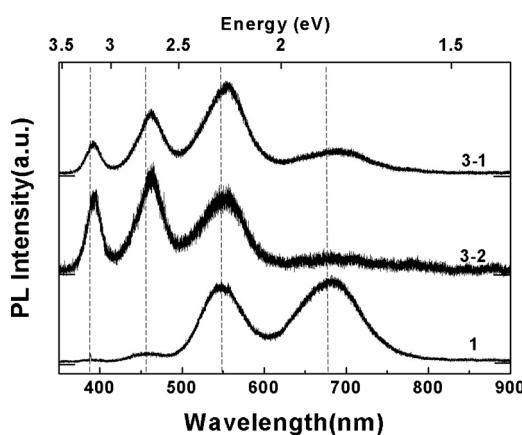


FIG. 3. PL data of the SrTiO₃ films after the low-T (50 °C) and long-term (>8 months) annealing of sample 1 and two pieces of sample 3 (3-1 and 3-2). The curves are shifted equally in the vertical axis.